MOSFET - Power, Single N-Channel, μ8FL **30 V, 3.6 m** Ω , **102 A**

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- NVTFS4C05NWF Wettable Flanks Product
- NVT Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Param	Symbol	Value	Unit		
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain Current R _{θJA}		T _A = 25°C	I _D	22	Α
(Notes 1, 2, 4)		T _A = 100°C		15.7	
Power Dissipation R _{θJA}		T _A = 25°C	P_{D}	3.2	W
(Notes 1, 2, 4)	Steady	T _A = 100°C		1.6	
Continuous Drain Current R _{ψJC}	State	T _C = 25°C	I _D	102	Α
(Notes 1, 3, 4)		T _C = 100°C		72	
Power Dissipation		T _C = 25°C	P_{D}	68	W
R _{ψJC} (Notes 1, 3, 4)		T _C = 100°C		34	
Pulsed Drain Current	T _A = 25°	C, t _p = 10 μs	I _{DM}	433	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	-55 to +175	°C
Source Current (Body Diode)			IS	65	Α
Single Pulse Drain-to-Source Avalanche Energy ($T_J = 25$ °C, $V_{GS} = 10$ V, $I_L = 18.8$ A, $L = 0.5$ mH)			E _{AS}	88	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain) (Notes 1, 3)	$R_{\psi JC}$	2.2	°C/W
Junction-to-Ambient - Steady State (Notes 1, 2)	$R_{ heta JA}$	47	

- 1. The entire application environment impacts the thermal resistance values shown; they are not constants and are valid for the specific conditions noted.
- Surface-mounted on FR4 board using 650 mm², 2 oz. Cu Pad.
- 3. Assumes heat-sink sufficiently large to maintain constant case temperature independent of device power.
- 4. Continuous DC current rating. Maximum current for pulses as long as one second is higher but dependent on pulse duration and duty cycle.

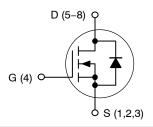


ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX
30 V	3.6 m Ω @ 10 V	102 A
	5.1 mΩ @ 4.5 V	102 A

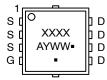
N-Channel MOSFET





MARKING DIAGRAM





4C05 = Specific Device Code for

NVMTS4C05N

= Specific Device Code of NVTFS4C05NWF

= Assembly Location

= Year = Work Week WW

= Pb-Free Package (Note: Microdot may be in either location)

ORDERING INFORMATION

See detailed ordering, marking and shipping information on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
OFF CHARACTERISTICS				•	•	•	•	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			٧	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				11.7		mV/°C	
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25°C			1.0		
		V _{DS} = 24 V	T _J = 125°C			10	μΑ	
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS}$	= ±20 V			±100	nA	
ON CHARACTERISTICS (Note 5)								
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$	= 250 μA	1.3		2.2	V	
Threshold Temperature Coefficient	V _{GS(TH)} /T _J				-5.0		mV/°C	
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		2.9	3.6	0	
		V _{GS} = 4.5 V	I _D = 30 A		4.1	5.1	mΩ	
Forward Transconductance	9 _{FS}	V _{DS} = 1.5 V, I _D	₎ = 15 A		68		S	
Gate Resistance	R _G	T _A = 25°0	С		1.0		Ω	
CHARGES AND CAPACITANCES								
Input Capacitance	C _{ISS}				1988		pF	
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1 MHz	z, V _{DS} = 15 V		1224			
Reverse Transfer Capacitance	C _{RSS}				71			
Capacitance Ratio	C _{RSS} /C _{ISS}	V _{GS} = 0 V, V _{DS} = 15 V, f = 1 MHz			0.036			
Total Gate Charge	Q _{G(TOT)}				14.5		nC	
Threshold Gate Charge	Q _{G(TH)}				2.9			
Gate-to-Source Charge	Q _{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 1$	5 V; I _D = 30 A		5.2			
Gate-to-Drain Charge	Q_{GD}				5.5			
Gate Plateau Voltage	V _{GP}				3.1		V	
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 1	5 V; I _D = 30 A		31		nC	
SWITCHING CHARACTERISTICS (Note 6)							
Turn-On Delay Time	t _{d(ON)}				11			
Rise Time	t _r	V _{GS} = 4.5 V, V _{DS}	s = 15 V,		30		- ns	
Turn-Off Delay Time	t _{d(OFF)}	$V_{GS} = 4.5 \text{ V}, V_{DS}$ $I_D = 15 \text{ A}, R_G = 10 \text{ A}$	= 3.0 Ω		20			
Fall Time	t _f				8.0			
Turn-On Delay Time	t _{d(ON)}				8.0			
Rise Time	t _r	$V_{GS} = 10 \text{ V}, V_{DS}$	s = 15 V,		25]	
Turn-Off Delay Time	t _{d(OFF)}	$I_D = 15 \text{ A}, R_G = 3.0 \Omega$			26		ns	
Fall Time	t _f				5.0			
DRAIN-SOURCE DIODE CHARACTERIS	TICS							
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V,	T _J = 25°C		0.77	1.1		
		I _S = 10 A	T _J = 125°C 0.62		V			
Reverse Recovery Time	t _{RR}	V_{GS} = 0 V, dIS/dt = 100 A/ μ s, I _S = 30 A			42.4			
Charge Time	ta				21.1		ns	
Discharge Time	t _b				21.3			
Reverse Recovery Charge	Q _{RR}				34.4		nC	

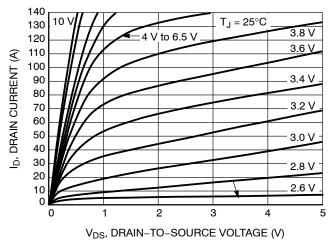
^{5.} Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

140

130

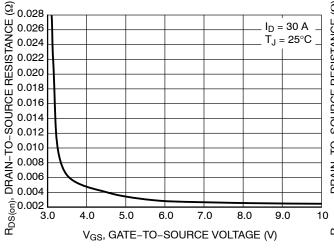
 $V_{DS} = 5 V$



120 110 ID, DRAIN CURRENT (A) 100 90 80 70 60 50 T_J = 125°C 40 30 T_J = 25°C 20 10 T_J = -55°C 0 0.5 1.5 2.0 2.5 3.0 3.5 V_{GS}, GATE-TO-SOURCE VOLTAGE (V)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



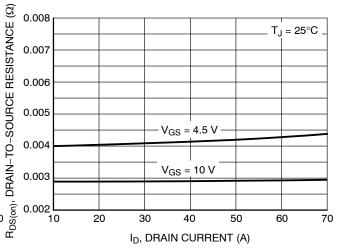
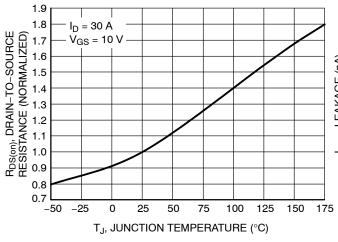


Figure 3. On-Resistance vs. V_{GS}

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



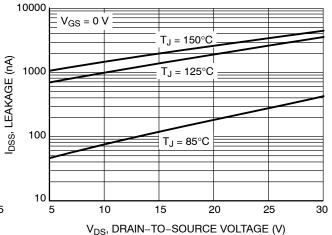


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

V_{GS}, GATE-TO-SOURCE VOLTAGE (V)

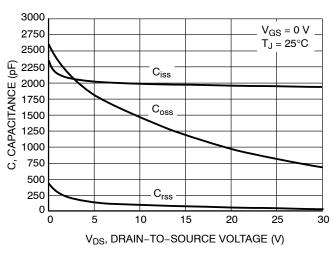


Figure 7. Capacitance Variation

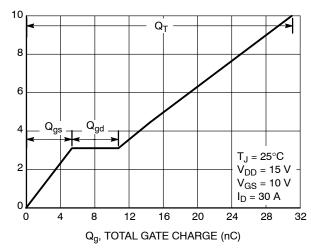


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

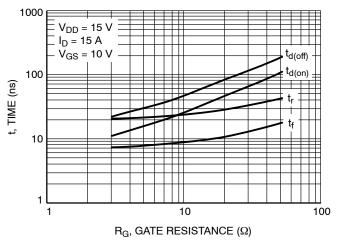


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

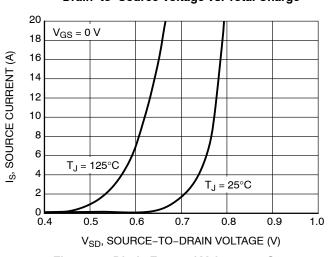


Figure 10. Diode Forward Voltage vs. Current

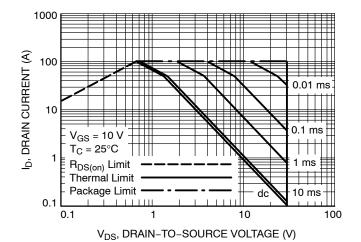


Figure 11. Maximum Rated Forward Biased Safe Operating Area

TYPICAL CHARACTERISTICS

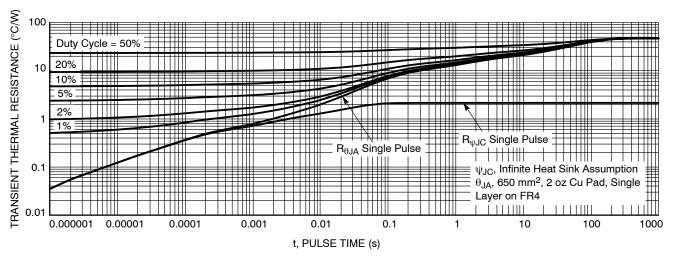


Figure 12. Thermal Response

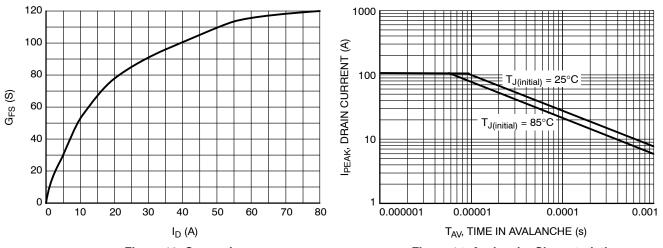


Figure 13. G_{FS} vs. I_D

Figure 14. Avalanche Characteristics

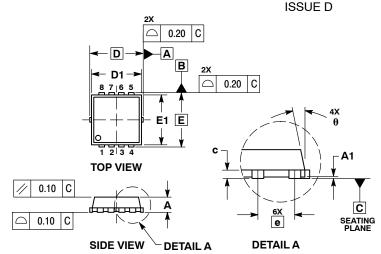
ORDERING INFORMATION

Device	Package	Shipping [†]
NVTFS4C05NTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel
NVTFS4C05NWFTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS

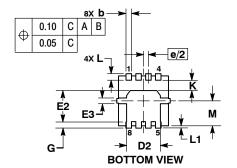
WDFN8 3.3x3.3, 0.65P CASE 511AB



NOTES

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.70	0.75	0.80	0.028	0.030	0.031
A1	0.00		0.05	0.000		0.002
b	0.23	0.30	0.40	0.009	0.012	0.016
С	0.15	0.20	0.25	0.006	0.008	0.010
D	3.30 BSC			O	.130 BSC)
D1	2.95	3.05	3.15	0.116	0.120	0.124
D2	1.98	2.11	2.24	0.078	0.083	0.088
E		3.30 BSC		0.130 BSC		
E1	2.95	3.05	3.15	0.116	0.120	0.124
E2	1.47	1.60	1.73	0.058	0.063	0.068
E3	0.23	0.30	0.40	0.009	0.012	0.016
е	0.65 BSC			0.026 BSC		
G	0.30	0.41	0.51	0.012	0.016	0.020
K	0.65	0.80	0.95	0.026	0.032	0.037
L	0.30	0.43	0.56	0.012	0.017	0.022
L1	0.06	0.13	0.20	0.002	0.005	0.008
М	1.40	1.50	1.60	0.055	0.059	0.063
θ	0 °		12 °	0 °		12 °



4X ⊢0.66 PACKAGE OUTLINE 3.60 0.75 0.57 2.30 0.47 2.37 3.46

SOLDERING FOOTPRINT*

DIMENSION: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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